

NGD18N40CLB, NGD18N40ACLB

Ignition IGBT, 18 A, 400 V N-Channel DPAK

This Logic Level Insulated Gate Bipolar Transistor (IGBT) features monolithic circuitry integrating ESD and Over-Voltage clamped protection for use in inductive coil drivers applications. Primary uses include Ignition, Direct Fuel Injection, or wherever high voltage and high current switching is required.

Features

- Ideal for Coil-on-Plug Applications
- DPAK Package Offers Smaller Footprint for Increased Board Space
- Gate-Emitter ESD Protection
- Temperature Compensated Gate-Collector Voltage Clamp Limits Stress Applied to Load
- Integrated ESD Diode Protection
- New Design Increases Unclamped Inductive Switching (UIS) Energy Per Area
- Low Threshold Voltage Interfaces Power Loads to Logic or Microprocessor Devices
- Low Saturation Voltage
- High Pulsed Current Capability
- Optional Gate Resistor (R_G) and Gate-Emitter Resistor (R_{GE})
- Emitter Ballasting for Short-Circuit Capability
- These are Pb-Free Devices

MAXIMUM RATINGS ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CES}	430	V_{DC}
Collector-Gate Voltage	V_{CER}	430	V_{DC}
Gate-Emitter Voltage	V_{GE}	18	V_{DC}
Collector Current-Continuous @ $T_C = 25^\circ\text{C}$ - Pulsed	I_C	15 50	A_{DC} A_{AC}
ESD (Human Body Model) $R = 1500 \Omega$, $C = 100 \text{ pF}$	ESD	8.0	kV
ESD (Machine Model) $R = 0 \Omega$, $C = 200 \text{ pF}$	ESD	800	V
Total Power Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	115 0.77	Watts $W/^\circ\text{C}$
Operating and Storage Temperature Range	T_J , T_{stg}	-55 to +175	$^\circ\text{C}$

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

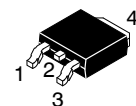
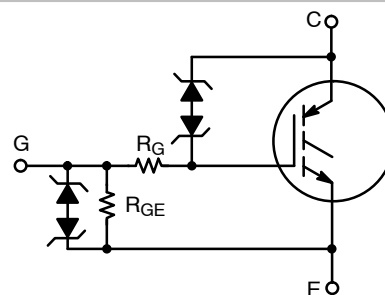


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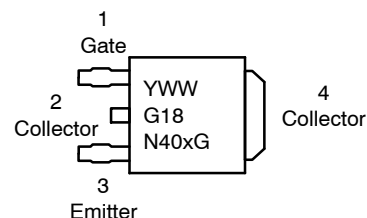
18 AMPS, 400 VOLTS

$V_{CE(on)} \leq 2.0 \text{ V @}$
 $I_C = 10 \text{ A}, V_{GE} \geq 4.5 \text{ V}$



**DPAK
CASE 369C
STYLE 7**

MARKING DIAGRAM



G18N40x = Device Code
x = B or A

Y = Year

WW = Work Week

G = Pb-Free Device

ORDERING INFORMATION

Device	Package	Shipping†
NGD18N40CLBT4G	DPAK (Pb-Free)	2500/Tape & Reel
NGD18N40ACLB T4G	DPAK (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

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UNCLAMPED COLLECTOR-TO-EMITTER AVALANCHE CHARACTERISTICS ($-55^{\circ}\text{C} \leq T_J \leq 175^{\circ}\text{C}$)

Characteristic	Symbol	Value	Unit
Single Pulse Collector-to-Emitter Avalanche Energy $V_{CC} = 50\text{ V}$, $V_{GE} = 5.0\text{ V}$, Pk $I_L = 21.1\text{ A}$, $L = 1.8\text{ mH}$, Starting $T_J = 25^{\circ}\text{C}$ $V_{CC} = 50\text{ V}$, $V_{GE} = 5.0\text{ V}$, Pk $I_L = 16.2\text{ A}$, $L = 3.0\text{ mH}$, Starting $T_J = 25^{\circ}\text{C}$ $V_{CC} = 50\text{ V}$, $V_{GE} = 5.0\text{ V}$, Pk $I_L = 18.3\text{ A}$, $L = 1.8\text{ mH}$, Starting $T_J = 125^{\circ}\text{C}$	E_{AS}	400 400 300	mJ
Reverse Avalanche Energy $V_{CC} = 100\text{ V}$, $V_{GE} = 20\text{ V}$, Pk $I_L = 25.8\text{ A}$, $L = 6.0\text{ mH}$, Starting $T_J = 25^{\circ}\text{C}$	$E_{AS(R)}$	2000	mJ

MAXIMUM SHORT-CIRCUIT TIMES ($-55^{\circ}\text{C} \leq T_J \leq 150^{\circ}\text{C}$)

Short Circuit Withstand Time 1 (See Figure 17, 3 Pulses with 10 ms Period)	t_{sc1}	750	μs
Short Circuit Withstand Time 2 (See Figure 18, 3 Pulses with 10 ms Period)	t_{sc2}	5.0	ms

THERMAL CHARACTERISTICS

Thermal Resistance, Junction to Case	$R_{\theta JC}$	1.3	$^{\circ}\text{C/W}$
Thermal Resistance, Junction to Ambient DPAK (Note 1)	$R_{\theta JA}$	95	$^{\circ}\text{C/W}$
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	T_L	275	$^{\circ}\text{C}$

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Temperature	Min	Typ	Max	Unit
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OFF CHARACTERISTICS

Collector-Emitter Clamp Voltage	BV_{CES}	$I_C = 2.0\text{ mA}$	$T_J = -40^{\circ}\text{C}$ to 150°C	380	395	420	V_{DC}
		$I_C = 10\text{ mA}$	$T_J = -40^{\circ}\text{C}$ to 150°C	390	405	430	
Zero Gate Voltage Collector Current	I_{CES}	$V_{CE} = 350\text{ V}$, $V_{GE} = 0\text{ V}$	$T_J = 25^{\circ}\text{C}$	-	2.0	20	μA_{DC}
			$T_J = 150^{\circ}\text{C}$	-	10	40*	
			$T_J = -40^{\circ}\text{C}$	-	1.0	10	
Reverse Collector-Emitter Leakage Current	I_{ECS}	$V_{CE} = -24\text{ V}$	$T_J = 25^{\circ}\text{C}$	-	0.7	1.0	mA
			$T_J = 150^{\circ}\text{C}$	-	12	25*	
			$T_J = -40^{\circ}\text{C}$	-	0.1	1.0	
Reverse Collector-Emitter Clamp Voltage	$BV_{CES(R)}$	$I_C = -75\text{ mA}$	$T_J = 25^{\circ}\text{C}$	27	33	37	V_{DC}
			$T_J = 150^{\circ}\text{C}$	30	36	40	
			$T_J = -40^{\circ}\text{C}$	25	32	35	
Gate-Emitter Clamp Voltage	BV_{GES}	$I_G = 5.0\text{ mA}$	$T_J = -40^{\circ}\text{C}$ to 150°C	11	13	15	V_{DC}
Gate-Emitter Leakage Current	I_{GES}	$V_{GE} = 10\text{ V}$	$T_J = -40^{\circ}\text{C}$ to 150°C	384	640	700	μA_{DC}
Gate Resistor	R_G	-	$T_J = -40^{\circ}\text{C}$ to 150°C	-	70	-	Ω
Gate Emitter Resistor	R_{GE}	-	$T_J = -40^{\circ}\text{C}$ to 150°C	10	16	26	k Ω

1. When surface mounted to an FR4 board using the minimum recommended pad size.

*Maximum Value of Characteristic across Temperature Range.

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ELECTRICAL CHARACTERISTICS (continued)

Characteristic	Symbol	Test Conditions	Temperature	Min	Typ	Max	Unit
ON CHARACTERISTICS (Note 2)							
Gate Threshold Voltage	$V_{GE(th)}$	$I_C = 1.0 \text{ mA}$, $V_{GE} = V_{CE}$	$T_J = 25^\circ\text{C}$	1.1	1.4	1.9	V_{DC}
			$T_J = 150^\circ\text{C}$	0.75	1.0	1.4	
			$T_J = -40^\circ\text{C}$	1.2	1.6	2.1*	
Threshold Temperature Coefficient (Negative)	-	-	-	-	3.4	-	mV/°C
Collector-to-Emitter On-Voltage	$V_{CE(on)}$	$I_C = 6.0 \text{ A}$, $V_{GE} = 4.0 \text{ V}$	$T_J = 25^\circ\text{C}$	1.0	1.4	1.6	V_{DC}
			$T_J = 150^\circ\text{C}$	0.9	1.3	1.6	
			$T_J = -40^\circ\text{C}$	1.1	1.45	1.7*	
		$I_C = 8.0 \text{ A}$, $V_{GE} = 4.0 \text{ V}$	$T_J = 25^\circ\text{C}$	1.3	1.6	1.9*	
			$T_J = 150^\circ\text{C}$	1.2	1.55	1.8	
			$T_J = -40^\circ\text{C}$	1.4	1.6	1.9*	
		$I_C = 10 \text{ A}$, $V_{GE} = 4.0 \text{ V}$	$T_J = 25^\circ\text{C}$	1.4	1.8	2.05	
			$T_J = 150^\circ\text{C}$	1.4	1.8	2.0	
			$T_J = -40^\circ\text{C}$	1.4	1.8	2.1*	
		$I_C = 15 \text{ A}$, $V_{GE} = 4.0 \text{ V}$	$T_J = 25^\circ\text{C}$	1.8	2.2	2.5	
			$T_J = 150^\circ\text{C}$	2.0	2.4	2.6*	
			$T_J = -40^\circ\text{C}$	1.7	2.1	2.5	
		$I_C = 10 \text{ A}$, $V_{GE} = 4.5 \text{ V}$	$T_J = 25^\circ\text{C}$	1.3	1.8	2.0*	
			$T_J = 150^\circ\text{C}$	1.3	1.75	2.0*	
			$T_J = -40^\circ\text{C}$	1.4	1.8	2.0*	
$I_C = 6.5 \text{ A}$, $V_{GE} = 3.7 \text{ V}$	$T_J = 25^\circ\text{C}$	-	-	1.65			
Forward Transconductance	gfs	$V_{CE} = 5.0 \text{ V}$, $I_C = 6.0 \text{ A}$	$T_J = -40^\circ\text{C}$ to 150°C	8.0	14	25	Mhos

DYNAMIC CHARACTERISTICS

Input Capacitance	C_{ISS}	$V_{CC} = 25 \text{ V}$, $V_{GE} = 0 \text{ V}$ $f = 1.0 \text{ MHz}$	$T_J = -40^\circ\text{C}$ to 150°C	400	800	1000	pF
Output Capacitance	C_{OSS}			50	75	100	
Transfer Capacitance	C_{RSS}			4.0	7.0	10	

SWITCHING CHARACTERISTICS

Turn-Off Delay Time (Resistive)	$t_{d(off)}$	$V_{CC} = 300 \text{ V}$, $I_C = 6.5 \text{ A}$ $R_G = 1.0 \text{ k}\Omega$, $R_L = 46 \Omega$	$T_J = 25^\circ\text{C}$	-	4.0	10	μSec
Fall Time (Resistive)	t_f	$V_{CC} = 300 \text{ V}$, $I_C = 6.5 \text{ A}$ $R_G = 1.0 \text{ k}\Omega$, $R_L = 46 \Omega$	$T_J = 25^\circ\text{C}$	-	9.0	15	
Turn-On Delay Time	$t_{d(on)}$	$V_{CC} = 10 \text{ V}$, $I_C = 6.5 \text{ A}$ $R_G = 1.0 \text{ k}\Omega$, $R_L = 1.5 \Omega$	$T_J = 25^\circ\text{C}$	-	0.7	4.0	μSec
Rise Time	t_r	$V_{CC} = 10 \text{ V}$, $I_C = 6.5 \text{ A}$ $R_G = 1.0 \text{ k}\Omega$, $R_L = 1.5 \Omega$	$T_J = 25^\circ\text{C}$	-	4.5	7.0	

2. Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2\%$.

*Maximum Value of Characteristic across Temperature Range.

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TYPICAL ELECTRICAL CHARACTERISTICS (unless otherwise noted)

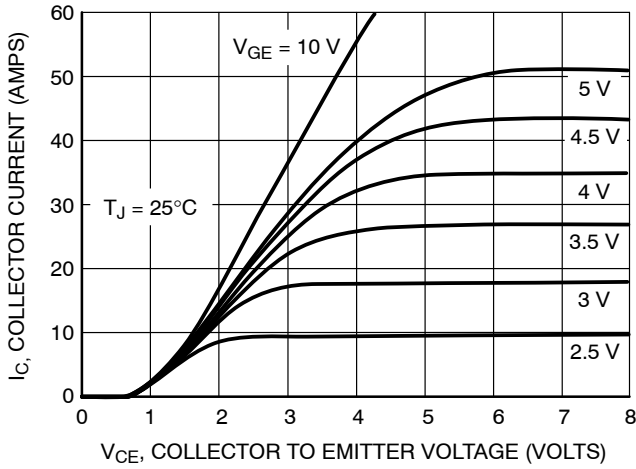


Figure 1. Output Characteristics

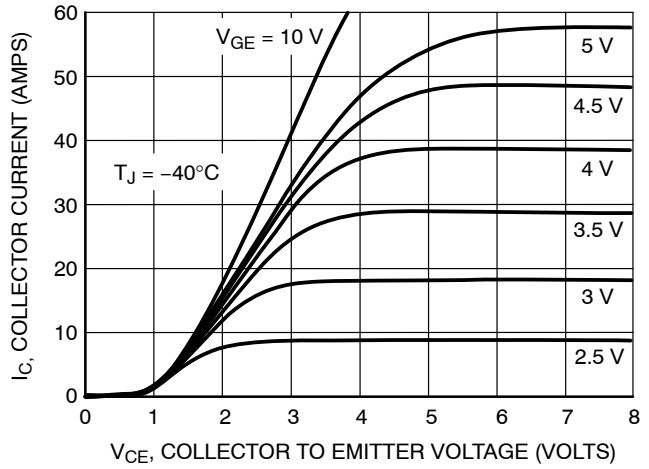


Figure 2. Output Characteristics

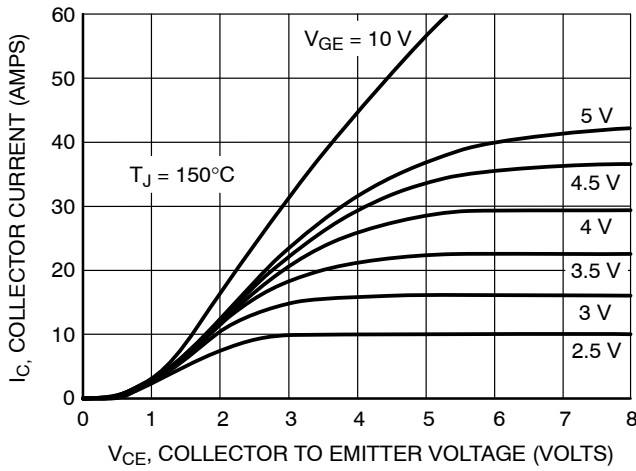


Figure 3. Output Characteristics

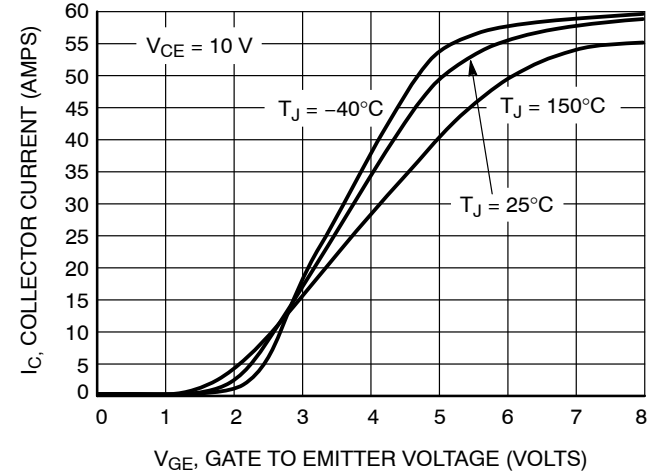


Figure 4. Transfer Characteristics

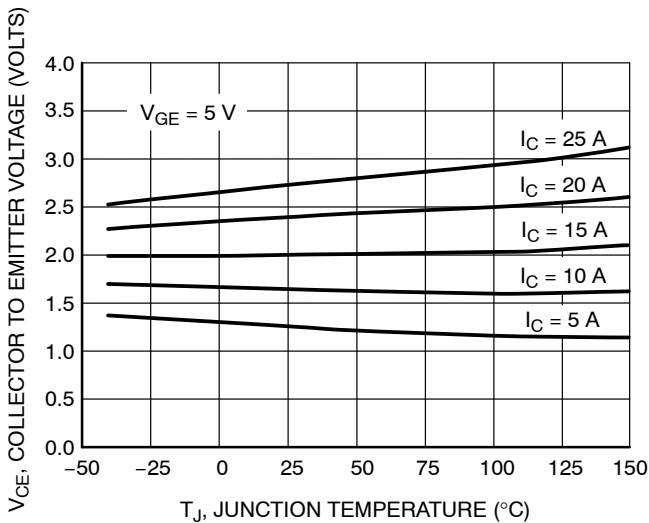


Figure 5. Collector-to-Emitter Saturation Voltage versus Junction Temperature

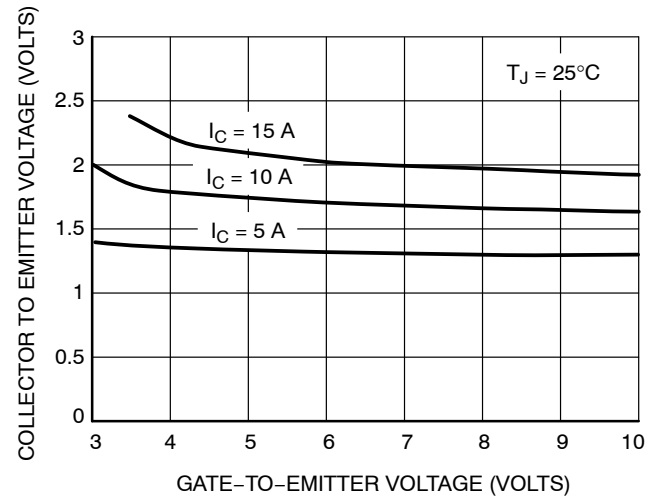


Figure 6. Collector-to-Emitter Voltage versus Gate-to-Emitter Voltage

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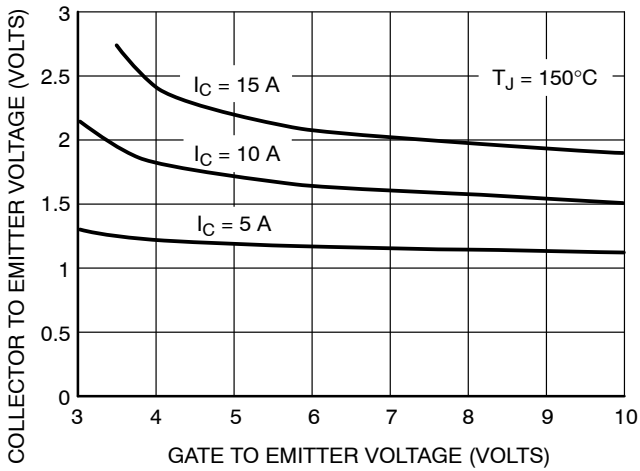


Figure 7. Collector-to-Emitter Voltage versus Gate-to-Emitter Voltage

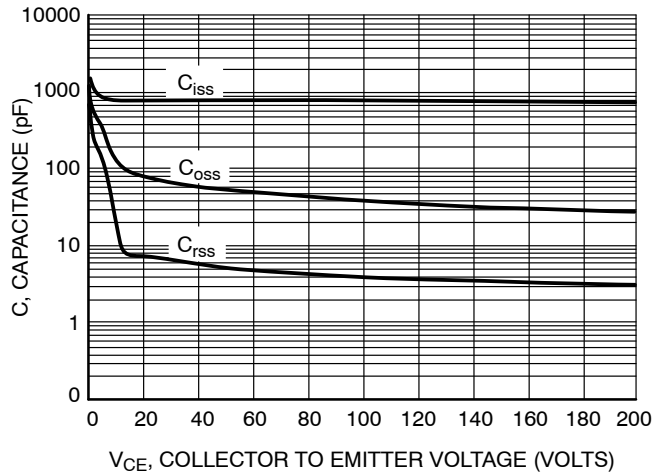


Figure 8. Capacitance Variation

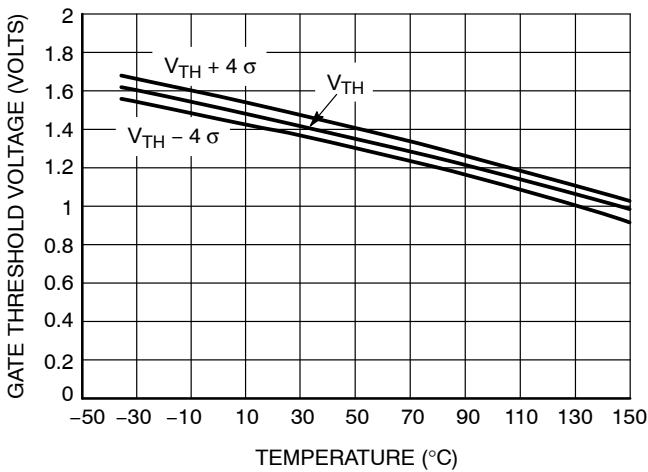


Figure 9. Gate Threshold Voltage versus Temperature

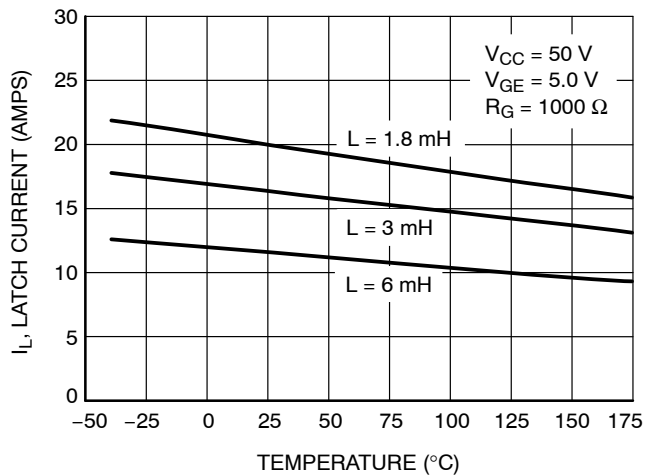


Figure 10. Minimum Open Secondary Latch Current versus Temperature

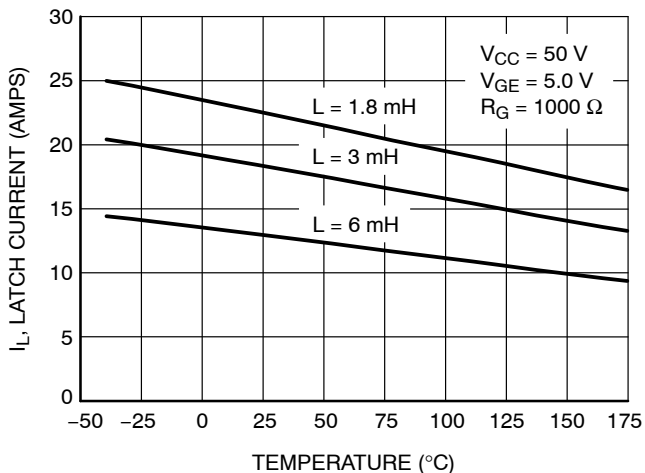


Figure 11. Typical Open Secondary Latch Current versus Temperature

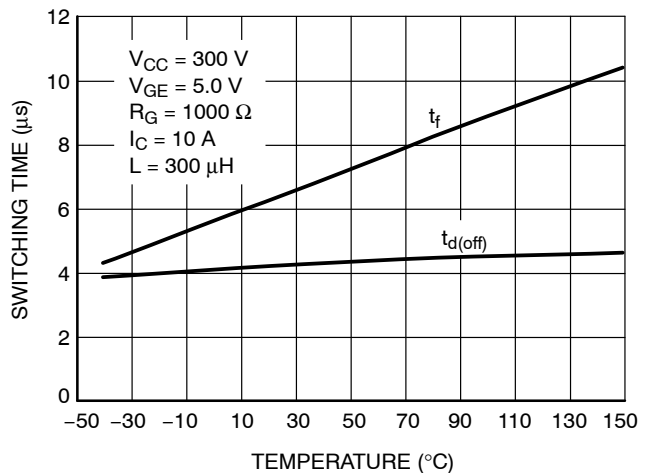


Figure 12. Inductive Switching Fall Time versus Temperature

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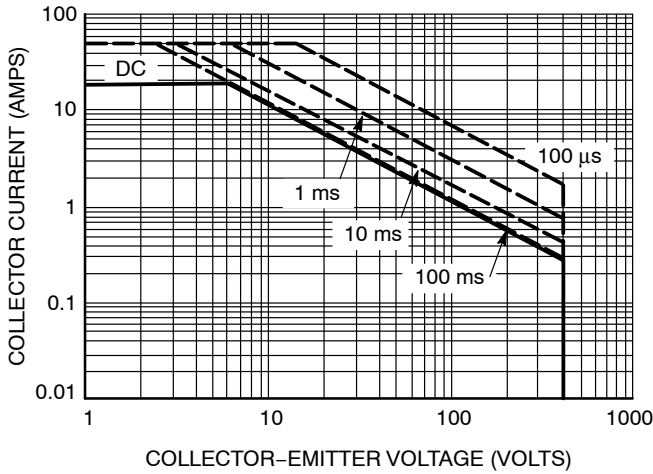


Figure 13. Single Pulse Safe Operating Area (Mounted on an Infinite Heatsink at $T_A = 25^\circ\text{C}$)

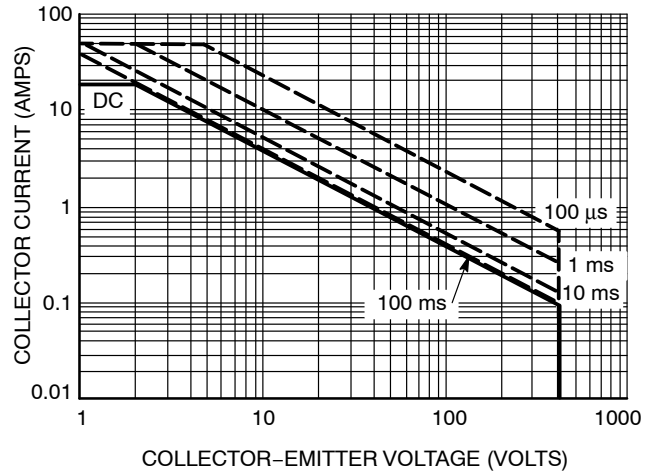


Figure 14. Single Pulse Safe Operating Area (Mounted on an Infinite Heatsink at $T_A = 125^\circ\text{C}$)

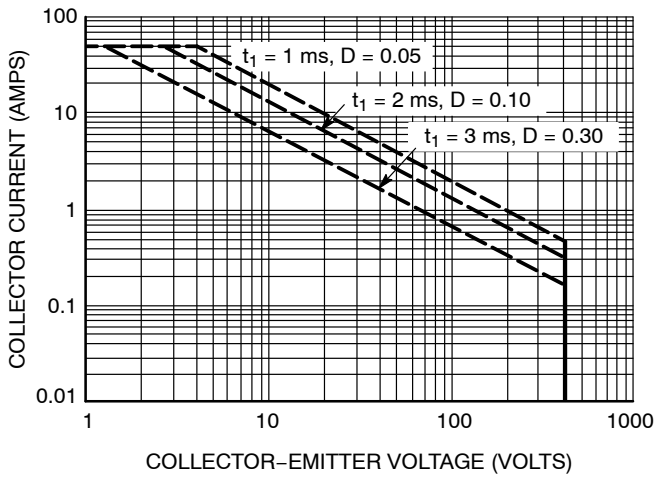


Figure 15. Pulse Train Safe Operating Area (Mounted on an Infinite Heatsink at $T_C = 25^\circ\text{C}$)

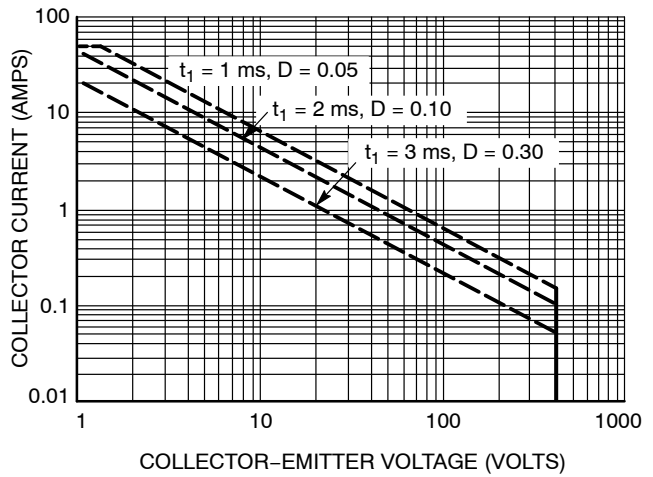


Figure 16. Pulse Train Safe Operating Area (Mounted on an Infinite Heatsink at $T_C = 125^\circ\text{C}$)

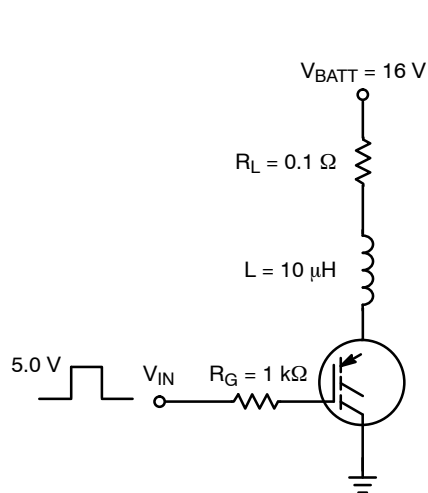


Figure 17. Circuit Configuration for Short Circuit Test #1

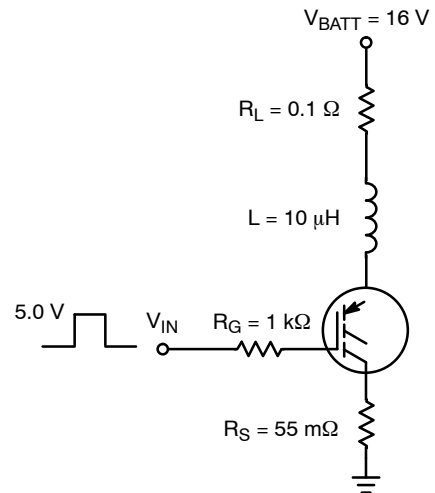
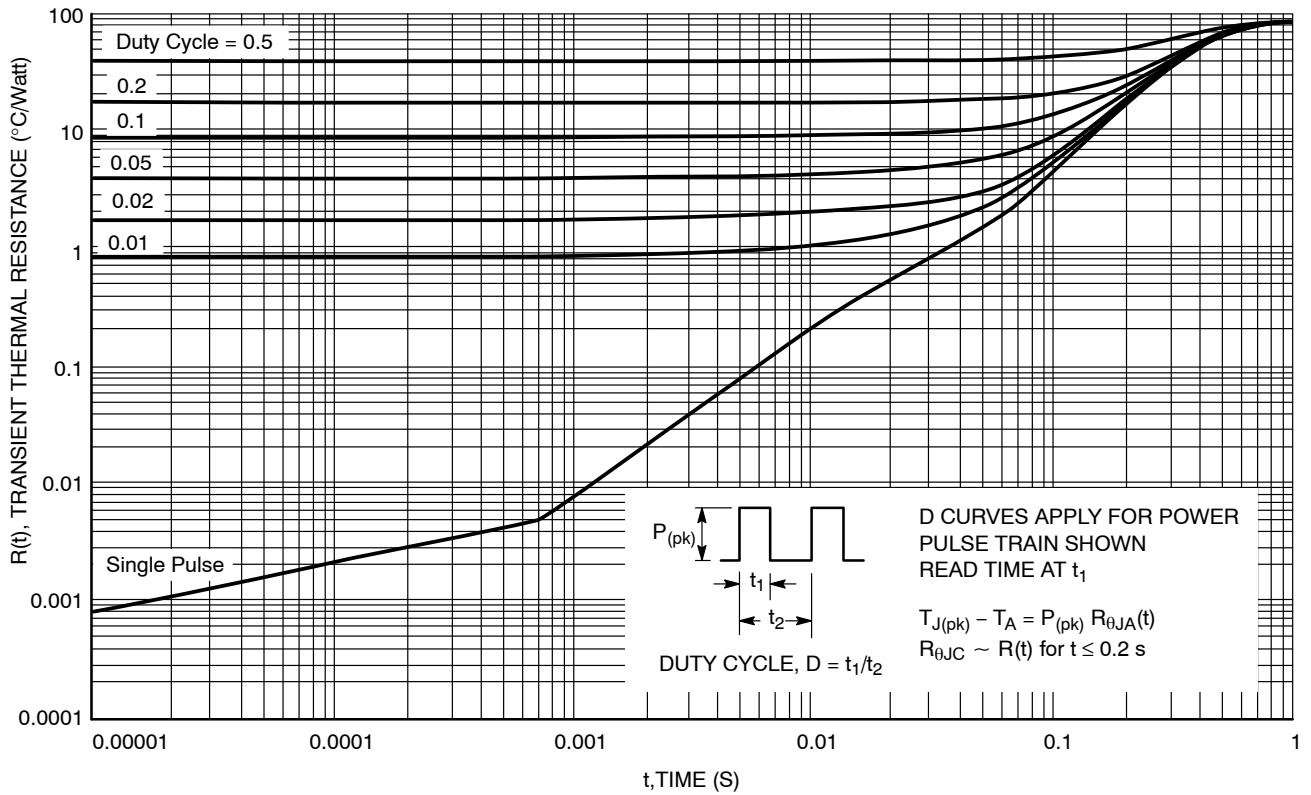


Figure 18. Circuit Configuration for Short Circuit Test #2

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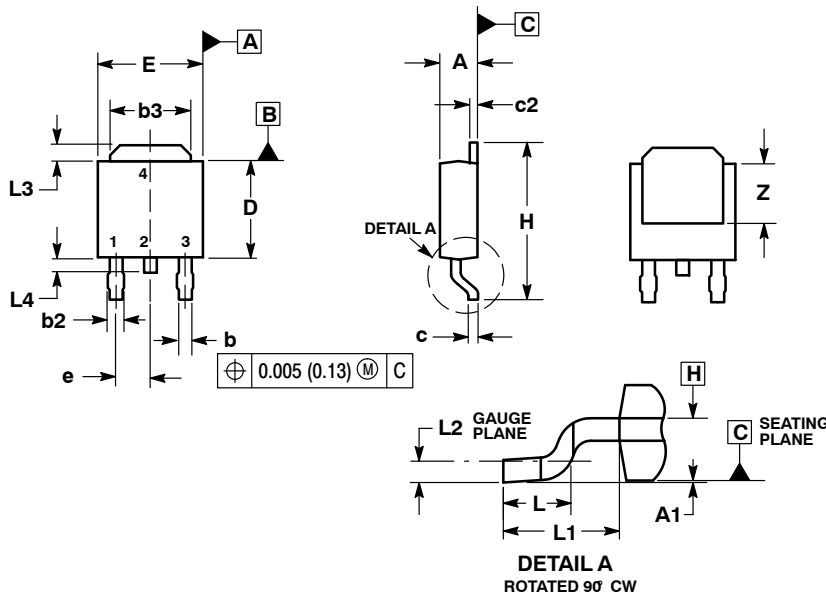


**Figure 19. Transient Thermal Resistance
(Non-normalized Junction-to-Ambient mounted on
minimum pad area)**

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PACKAGE DIMENSIONS

DPAK CASE 369C ISSUE D



NOTES:

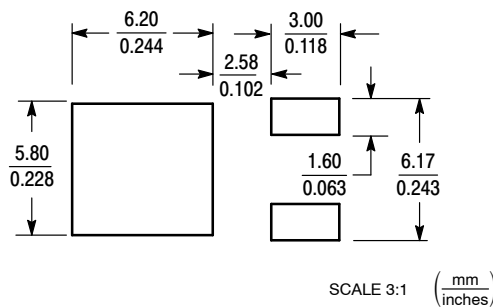
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: INCHES.
3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
c	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
e	0.090	BSC	2.29	BSC
H	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	REF	2.74	REF
L2	0.020	BSC	0.51	BSC
L3	0.035	0.050	0.89	1.27
L4	---	0.040	---	1.01
Z	0.155	---	3.93	---

STYLE 7:

- PIN 1. GATE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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